Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/798,709	LICON ET AL.	
Examiner	Art Unit	
Paul Kim	2161	

	SEARCHED		
Class	Subclass	Date	Examiner
707	3	7/25/2007	PK
	, , , , , ,		•
	٠	•	
		,	
			-

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			•
			1

SEARCH N (INCLUDING SEAR)		')
	DATE	EXMR
See EAST Search History	7/25/2007	PK
· .		
·		
		E